

**July 2014** 

# FDFMA3P029Z

# Integrated P-Channel PowerTrench® MOSFET and Schottky Diode

 $-30 \text{ V}, -3.3 \text{ A}, 87 \text{ m}\Omega$ 

### **Features**

#### **MOSFET**

- Max  $r_{DS(on)}$  = 87 m $\Omega$  at  $V_{GS}$  = -10 V,  $I_D$  = -3.3 A
- Max  $r_{DS(on)} = 152 \text{ m}\Omega$  at  $V_{GS} = -4.5 \text{ V}$ ,  $I_D = -2.3 \text{ A}$
- HBM ESD protection level > 2 KV typical (Note 3)

#### Schottky

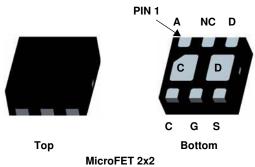
- V<sub>F</sub> < 0.37 V @ 500 mA
- Low profile 0.8 mm maximum in the new package MicroFET 2x2 mm
- RoHS Compliant

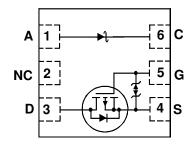
## **General Description**

This device is designed specifically as a single package solution for the battery charge switch in cellular handset and other ultra-portable applications. It features a MOSFET with very low on-state resistance and an independently connected low forward voltage schottky diode allows for minimum conduction losses.

The MicroFET 2X2 package offers exceptional thermal performance for its physical size and is well suited to linear mode applications.







### MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Parameter	Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage	-30	V
V <sub>GS</sub>	Gate to Source Voltage	±25	V
1	Drain Current -Continuous (Note	-3.3	^
ID	-Pulsed	-15	A
D	Power Dissipation (Note	1.4	W
$P_{D}$	(Note	1b) 0.7	] VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range	-55 to +150	°C
$V_{RRM}$	Schottky Repetitive Peak Reverse Voltage	20	V
lo	Schottky Average Forward Current	2	Α

#### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	86	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	173	00/14/
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1c)	86	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1d)	173	

### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
3P2	FDFMA3P029Z	MicroFET 2X2	7 "	8 mm	3000 units

# **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu A$ , referenced to 25 °C		-22		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -24 \text{ V}, \ V_{GS} = 0 \text{ V}$			-1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μА

### **On Characteristics**

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = -250 \mu A$	-1.3	-1.9	-2.3	V	
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = -250 \mu A$ , referenced to 25 °C		5		mV/°C	
	$V_{GS} = -10 \text{ V}, I_D = -3.3 \text{ A}$		69	87			
rno()	Static Drain to Source On-Resistance	$V_{GS} = -4.5 \text{ V},  I_D = -2.3 \text{ A}$		108	152	mΩ	
r <sub>DS(on)</sub> Static Drain to Source On-Hesistance	$V_{GS} = -10 \text{ V}, I_D = -3.3 \text{ A},$ $T_J = 125 \text{ °C}$		97	122	11122		
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = -5 \text{ V}, I_{D} = -3.3 \text{ A}$		6		S	
$R_g$	Gate Resistance			12		Ω	

## **Dynamic Characteristics**

(	C <sub>iss</sub>	Input Capacitance	V 45 V V 0 V	324	435	pF
(	C <sub>oss</sub>	Output Capacitance	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz	59	80	pF
(	$C_{rss}$	Reverse Transfer Capacitance	1 = 1 WITZ	53	80	pF

### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		5.2	11	ns
t <sub>r</sub>	Rise Time	$V_{DD} = -15 \text{ V}, I_{D} = -3.3 \text{ A}$ $V_{GS} = -10 \text{ V}, R_{GEN} = 6 \Omega$	3	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = -10 V, n <sub>GEN</sub> = 0 12	17	31	ns
t <sub>f</sub>	Fall Time		11	25	ns
0	Total Gate Charge	V <sub>GS</sub> = 0 V to -10 V	7.2	10	nC
$Q_{g(TOT)}$	Total Gate Charge	$V_{GS} = 0 \text{ V to } -5 \text{ V}$ $V_{DD} = -15 \text{ V},$	4.1	6	
$Q_{gs}$	Gate to Source Gate Charge	I <sub>D</sub> = -3.3 A	1.0		nC
$Q_{gd}$	Gate to Drain "Miller" Charge		1.9		nC

## **Drain-Source Diode Characteristics**

$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = -3.3 \text{ A}$ (Note 2)	-0.94	-1.3	V
t <sub>rr</sub>	Reverse Recovery Time	- I <sub>E</sub> = -3.3 A, di/dt = 100 A/μs	20	32	ns
$Q_{rr}$	Reverse Recovery Charge	$I_{\rm F} = -3.3  \text{A},  \text{di/dt} = 100  \text{A/} \mu \text{S}$	10	18	nC

# **Schottky Diode Characteristics**

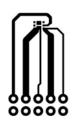
$V_R$	Reverse Voltage	$I_R = 1 \text{ mA}$	$T_J = 25  ^{\circ}C$	20			V
L Dougrap Lookage	Reverse Leakage	V <sub>R</sub> = 20 V	T <sub>J</sub> = 25 °C		30	300	μА
<sup>I</sup> R	neverse Leakage	v <sub>R</sub> = 20 v	T <sub>J</sub> = 125 °C		10	45	mA
	I - 500 m	I <sub>E</sub> = 500 mA	T <sub>J</sub> = 25 °C		0.32	0.37	
VE	Forward Voltage	IF = 300 IIIA	T <sub>J</sub> = 125 °C		0.21	0.26	v
٧F	l of ward voitage	Ι 1 Δ	T <sub>J</sub> = 25 °C		0.37	0.435	v
		I <sub>F</sub> = 1 A	T <sub>J</sub> = 125 °C		0.28	0.33	

#### Notes:

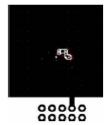
- 1:  $R_{\text{NJA}}$  is determined with the device mounted on a 1 in<sup>2</sup> oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{\text{NJC}}$  is guaranteed by design while  $R_{\text{NJA}}$  is determined by the
  - (a) MOSFET  $R_{\theta,JA} = 86$  °C/W when mounted on a 1in<sup>2</sup> pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB
  - (b) MOSFET  $R_{\theta JA}$  = 173 °C/W when mounted on a minimum pad of 2 oz copper
  - (c) Schottky  $R_{\theta JA} = 86$  °C/W when mounted on a 1in<sup>2</sup> pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB.
  - (d) Schottky  $R_{\theta JA}$  = 173 °C/W when mounted on a minimum pad of 2 oz copper.



a)86 °C/W when mounted on a 1in<sup>2</sup> pad of 2 oz copper.



b)173 °C/W when mounted on a minimum pad of 2 oz



c)86 °C/W when mounted on a 1in<sup>2</sup> pad of 2 oz copper.



d)173 °C/W when mounted on a minimum pad of 2 oz copper.

- 2: Pulse Test : Pulse Width < 300  $\mu$ s, Duty Cycle < 2.0% 3: The diode connected between the gate and source serves only protection against ESD. No gate overvoltage rating is implied.

## Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

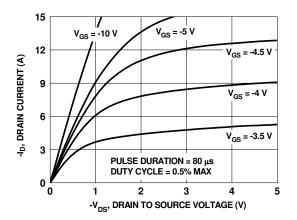


Figure 1. On-Region Characteristics

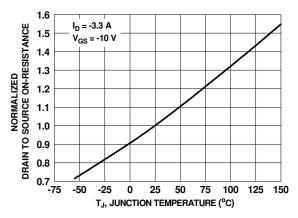


Figure 3. Normalized On-Resistance vs Junction Temperature

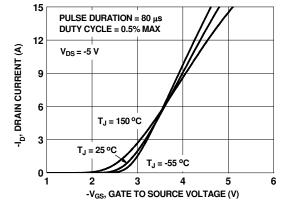


Figure 5. Transfer Characteristics

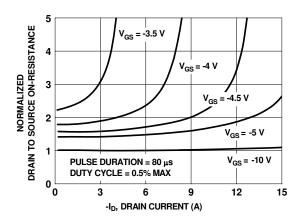


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

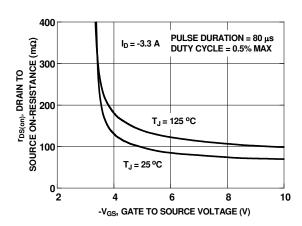


Figure 4. On-Resistance vs Gate to Source Voltage

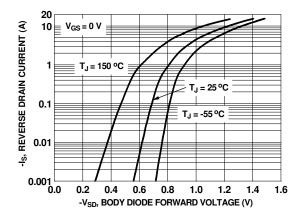


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

## **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

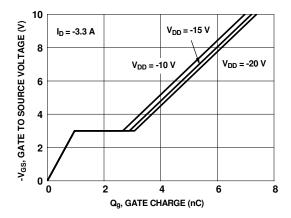


Figure 7. Gate Charge Characteristics

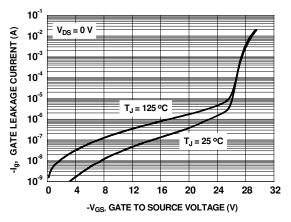


Figure 9. Gate Leakage Current vs Gate to Source Voltage

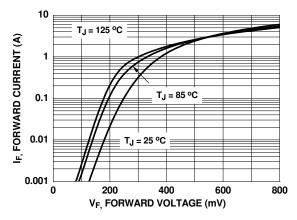


Figure 11. Schottky Diode Forward Voltage

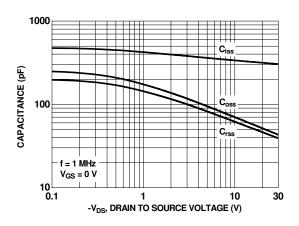


Figure 8. Capacitance vs Drain to Source Voltage

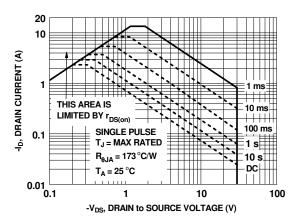


Figure 10. Forward Bias Safe Operating Area

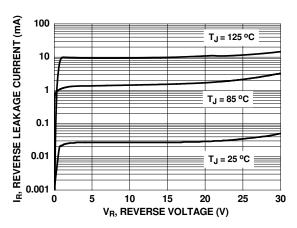


Figure 12. Schottky Diode Reverse Current



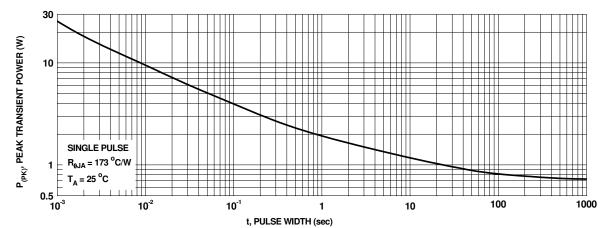


Figure 13. Single Pulse Maximum Power Dissipation

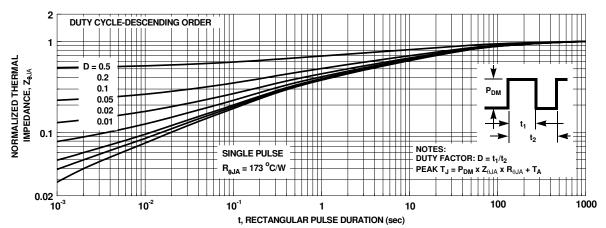
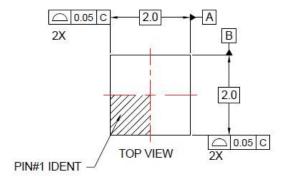
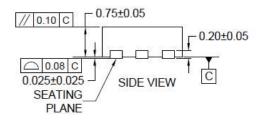
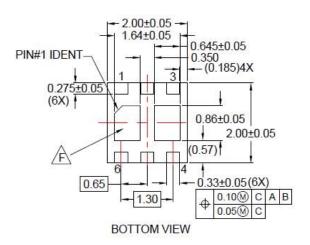


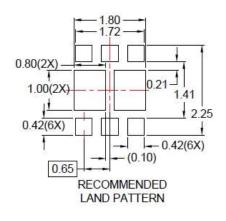
Figure 14. Junction-to-Ambient Transient Thermal Response Curve

### **Dimensional Outline and Pad Layout**









#### NOTES:

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- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
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Rev. 168